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**AEHR TEST SYSTEMS RECEIVES FOLLOW-ON FOX™ ORDERS  
FROM A MAJOR IC MANUFACTURER**

**Fremont, CA (January 4, 2007) - Aehr Test Systems (Nasdaq: AEHR)**, a leading supplier of semiconductor test and burn in equipment, today announced it has received repeat orders from a leading memory IC manufacturer totaling over \$6 million for its FOX-1 full wafer parallel test systems and its full wafer contactors. The systems and contactors are scheduled to ship during the next six months.

“It is very significant that these orders are for FOX-1 parallel testers configured for testing 300mm wafers,” said Greg Perkins, vice president of worldwide sales and service at Aehr Test Systems. “We believe this is a very important development for us, as the system updates required to test 300mm wafers expand our ability to address new markets and customer needs.”

The FOX-1 full wafer parallel test system, a member of the FOX family of full wafer contact systems, is designed to test an entire wafer of IC devices in a single touchdown or utilized for short burn-in and test applications. This innovative solution combines full wafer contact, massively parallel test and Design For Test (DFT) technologies. Other members of Aehr Test’s FOX family of products such as the FOX-14 and FOX-V, are focused on long-duration full wafer burn-in and test of products such as automotive ICs, DRAMs and VCSELs (laser diodes).

**About Aehr Test Systems**

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX, MTX and MAX systems and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company’s website at [www.aehr.com](http://www.aehr.com).

**Safe Harbor Statement**

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX technology, acceptance by customers of the FOX systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K and 10-Q reports and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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